

Data sheet acquired from Harris Semiconductor SCHS036B - Revised July 2003

# CMOS 64-Stage Static Shift Register

High-Voltage Types (20-Volt Rating)

■ CD4031B is a static shift register that contains 64 D-type, master-slave flipflop stages and one stage which is a D-type master flip-flop only (referred to as a 1/2 stage).

The logic level present at the DATA input is transferred into the first stage and shifted one stage at each positive-going clock transition. Maximum clock frequencies up to 12 Megahertz (typical) can be obtained. Because fully static operation is allowed, information can be permanently stored with the clock line in either the low or high state. The CD4031B has a MODE CONTROL input that, when in the high state, allows operation in the recirculating mode. The MODE CON-TROL input can also be used to select between two separate data sources. Register packages can be cascaded and the clock lines driven directly for high-speed operation. Alternatively, a delayed clock output (CLD) is provided that enables cascading register packages while allowing reduced clock drive fan-out and transition-time requirements. A third cascading option makes use of the Q' output from the 1/2 stage, which is available on the next negative-going transition of the clock after the Q output occurs. This delayed output, like the delayed clock CLD, is used with clocks having slow rise and fall times.

The CD4031B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (NSR suffix), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

## Features:

- Fully static operation: DC to 12 MHz typ. @ V<sub>DD</sub>-V<sub>SS</sub> = 15 V
- Standard TTL drive capability on Q output
- Recirculation capability
- Three cascading modes:

Direct clocking for high-speed operation Delayed clocking for reduced clock drive requirements Additional 1/2 stage for slow clocks

- 100% tested for quiescent current at 20 V
- Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range)

1 V at V<sub>DD</sub> = 5 V 2 V at V<sub>DD</sub> = 10 V 2.5 V at V<sub>DD</sub> = 15 V

- 5-V. 10-V. and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 138, "Standard Specifications for Description of 'B' Series CMOS Devices'

#### Applications:

- Serial shift registers
- Time delay circuits

#### RECOMMENDED OPERATING CONDITIONS For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

	LIN		
CHARACTERISTIC	Min.	Max.	UNITS
Supply-Voltage Range (For T <sub>A</sub> =Full Package- Temperature Range)	3	18	V

# DATA I 15 MODE 10 CLOCK V<sub>SS</sub> = 8 NC = 3,4,11,12,13,14 92C5 - 29039R **FUNCTIONAL DIAGRAM**

#### INPUT CONTROL CIRCUIT TRUTH TABLE

CD4031B Types

DATA	RECIRC.	MODE	BIT INTO STAGE I
1	x	0	1
0	Х	0	0
X	1	1	1
Х	0	1	0

#### TYPICAL STAGE TRUTH TABLE

Deta	CL	Data + 1
0	<b>-</b>	0
1		1
×		NC

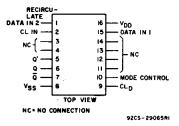
#### TRUTH TABLE FOR OUTPUT FROM Q' (TERMINAL 5)

Data + 64	CL	Data + 64½
0		0
1	7	1
X.		NC

1 = HIGH LEVEL

0 = LOW LEVEL

X = DON'T CARE NC = NO CHANGE



TERMINAL ASSIGNMENT

#### MAXIMUM RATINGS, Absolute-Maximum Values: DC SUPPLY-VOLTAGE RANGE, (VDD) Voltages referenced to VSS Terminal) ......-0.5V to +20V INPUT VOLTAGE RANGE, ALL INPUTS .....-0.5V to VDD +0.5V POWER DISSIPATION PER PACKAGE (PD): For TA = +100°C to +125°C...... Derate Linearity at 12mW/°C to 200mW DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) ...... 100mW OPERATING-TEMPERATURE RANGE (TA).....-55°C to +125°C STORAGE TEMPERATURE RANGE (Tstg).....-65°C to +150°C LEAD TEMPERATURE (DURING SOLDERING):

STATIC E	LECTRICAL	CHARACTERISTICS

AU	CONDITIONS		LIMITS AT INDICATED TEMPERATURES (°C)						UNITS		
CHARACTERISTIC	Vo	VIN	$v_{DD}$						+25		
	(V)	(V)	(V)	_ <u>5</u> 5	-40	+85	+125	Min.	Typ.	Max.	
Quiescent Device	_	0,5	5	5	5	150	150	_	0.04	5	
Current,	'	0,10	10	10	10	300	300	_	0.04	10	μΑ
IDD Max.		0,15	15	20	20	600	600	- /	0.04	20	
		0,20	20	100	100	3000	3000	-	0.08	100	
Output Low (Sink)	0.4	0,5	5	2.56	2.44	1.68	1.44	2.04	4	-	
Current IOL Min.	0.5	0,10	10	6.4	6	4.4	3.6	5.2	10.4	-	
u	1.5	0,15	15	16.8	16	11.2	9.6	13.6	27.2	_	٠,٠
	0.4	0,5	5	0.64	0:61	0.42	0.36	0.51	1	_	1
α, α, c <sub>LD</sub>	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	-	ł
_	1.5	0,15	15	4.2	4 ·	2.8	2.4	3.4	6.8	-	mA.
Output High (Source)	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	-	1 .
Current, l <sub>OH</sub> Min. Q, Q, Q', CLD	2.5	0,5	5	- 2	1.8	1.3	-1.15	-1.6	-3.2.		1
	9.5	0,10	10	- 1.6	1.5	-1.1	-0.9	-1.3	-2.6	-	1
	13.5	0,15	15	4.2	4	2.8	-2.4	-3.4	-6.8	-	
Output Voltage:	-	0,5	5			0.05		_	0	0.05	
Low Level.	×:	0,10	10	:		0.05		-	0	0.05	1
VOL Max.		0,15	15	*		0.05		_	. 0	0.05	l v
Output Voltage:	-	0,5				4.95		4.95	5		l '
High Level,	·	0,10				9.95		9.95	10	_	
V <sub>OH</sub> Min,		0,15				14.95		14.95	15		
Input Low	0.5, 4.5	-	5			1.5		-		1.5	
Voltage	1,9	-	10			3				3	,
V <sub>IL</sub> Max.	1.5, 13.5	-	15			4				4	V
Input High	0.5, 4.5		5			3.5		3.5	<u> </u>		•
Voltage,	1;9	-	10			7		7	<b>├</b> <u>¯</u>		ł
V <sub>IH</sub> Min.	1.5, 13.5		15	<del></del>		11		11		_	<u> </u>
Input Current I <sub>IN</sub> Max.		0,18	18	±0.1	±0.1	±1	±1	_	±10-5	±0.1	μΑ

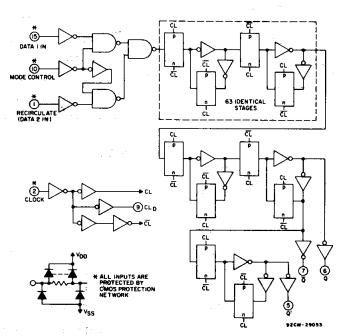


Fig. 1 — Logic diagram.

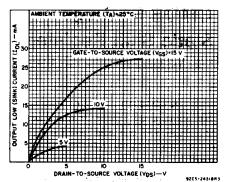


Fig. 2 — Typical output low (sink)

current characteristics (Q sink

current = 4X ordinate).

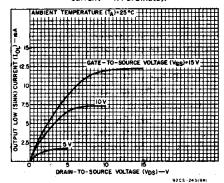


Fig. 3 — Minimum output low (sink)
current characteristics (Q sink
current = 4X ordinate).

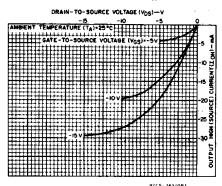


Fig. 4 — Typical output high (source) current characteristics.

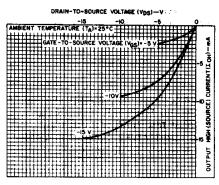


Fig. 5 — Minimum output high (source) current characteristics.

## CD4031B Types

DYNAMIC ELECTRICAL CHARACTERISTICS at  $T_A$  = 25°C; Input  $t_r$ ,  $t_f$  = 20 ns,  $C_L$  = 50 pF,  $R_L$  = 200 k $\Omega$ 

CHARACTERISTIC	TEST CONDITIONS	LIMITS				
CHARACTERISTIC	V <sub>DD</sub> (V)	Min.	Тур.	Max.	UNITS	
Propagation Delay Time:	5	_	250	500		
Clock to Q, tpHL, tpLH;	10	-	110	220	ns	
Clock to Q, tPLH	15	_	90	180		
Clock to Q', tpHL, tpLH;	5	-	190	380	``	
Clock to Q, tpHL	10	_	80	160	ns	
	15		65	130		
,	5	_	100	200		
Clock to CL <sub>D</sub>	10		50	100	ns	
	15		40	80		
Transition Time t	5		100	200		
Transition Time, t <sub>THL</sub> , t <sub>TLH</sub>	10	_	50	100	ns	
(Any Output, except Q, tTHL)	15	_	40	80		
Q, t <sub>THL</sub>	5	_	50	100		
	10	_	25	50	ns	
	15		20	40		
	5	_	30	60		
Minimum Data Setup Time, tS	10	_	15	30	ns ns	
	15	-	10	20		
	5	_	30	60		
Minimum Data Hold Time, tH	10	_	15	30	กร	
<u>-</u>	15	-	10	20		
	5	_	120	240		
Minimum Clock Pulse Width, tw	10	_	50	100	ns	
	15	-	40	80		
Marrian Challe In and En	5	2	4	_		
Maximum Clock Input Frequency,	10	5	10		MHz	
fcL**	. 15	6	12	-		
Clark Inquit Bios on Sall Time	5		<u> </u>	1000		
Clock Input Rise or Fall Time,	10		_	1000	μs	
trCL/tfCL*	15		-	200	·	
Input Capacitance, C <sub>IN</sub> (Any Input)		_	5	7.5	pF	

<sup>\*</sup>If more than one unit is cascaded in the parallel clocked application, t<sub>r</sub>CL should be made less than or equal to the sum of the propagation delay at 50 pF and the transition time of the output driving stage. \*\*Maximum Clock Frequency for Cascaded Units;



 $f_{\text{max}} = \frac{1}{\text{(n-1) CL}_D \text{ prop. delay + Q prop. delay + set-up time}}$  where n = number of packages

b) Not Using Delayed Clock:

fmax = propagation delay + set-up time

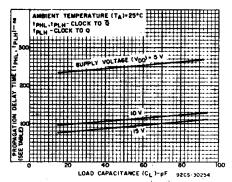


Fig. 6 — Typical propagation delay time as a function of load capacitance (see table).

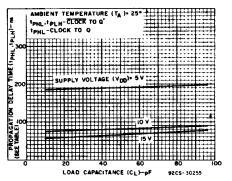


Fig. 7 — Typical propagation delay time as a function of load capacitance (see table).

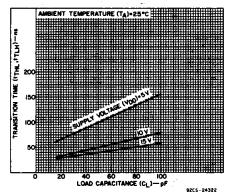


Fig. 8 — Typical transition time as a function of load capacitance (except Q, t<sub>THL</sub>).

## CD4031B Types

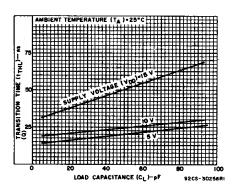


Fig. 9 — Typical transition time as a function of load capacitance (Q,  $t_{THL}$ ).

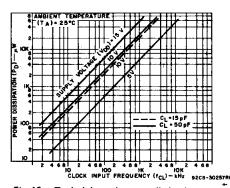


Fig. 10 — Typical dynamic power dissipation as a function of clock input frequency.

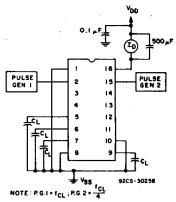


Fig. 11 - Dynamic power dissipation test circuit.

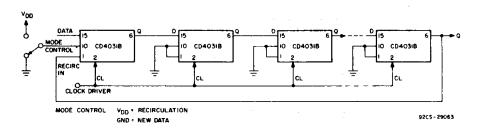


Fig. 12 — Cascading using direct clocking for high-speed operation (see clock rise and fall time requirement).

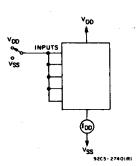


Fig. 13 — Quiescent-devicecurrent test circuit.

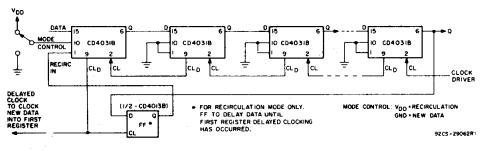


Fig. 14 - Cascading using delayed clocking for reduced clock drive requirements.

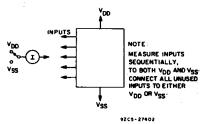


Fig. 15 - Input-leakage current.

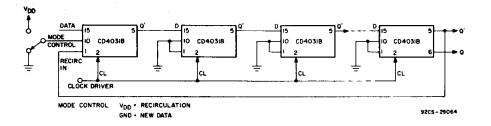


Fig. 16 — Cascading using half-clock-pulse delayed data output  $(Q^\prime)$  to permit use of slow rise and fall time clock inputs.

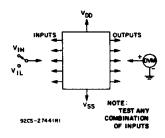
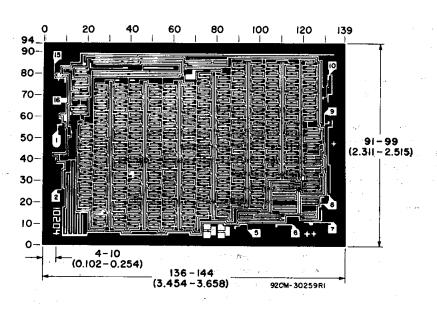


Fig. 17 - Input-voltage test circuit.



#### Chip dimensions and ped layout for CD4031B

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10<sup>-3</sup> inch).

## 14 LEADS SHOWN



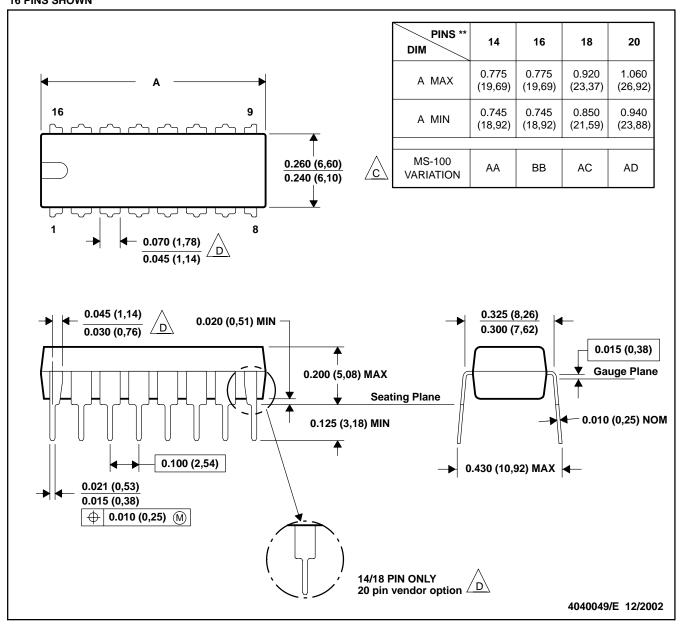
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

## N (R-PDIP-T\*\*)

## 16 PINS SHOWN

#### PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

Falls within JEDEC MS-001, except 18 and 20 pin minimum body Irngth (Dim A).

The 20 pin end lead shoulder width is a vendor option, either half or full width.

1

## **MECHANICAL DATA**

## NS (R-PDSO-G\*\*)

## 14-PINS SHOWN

## PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

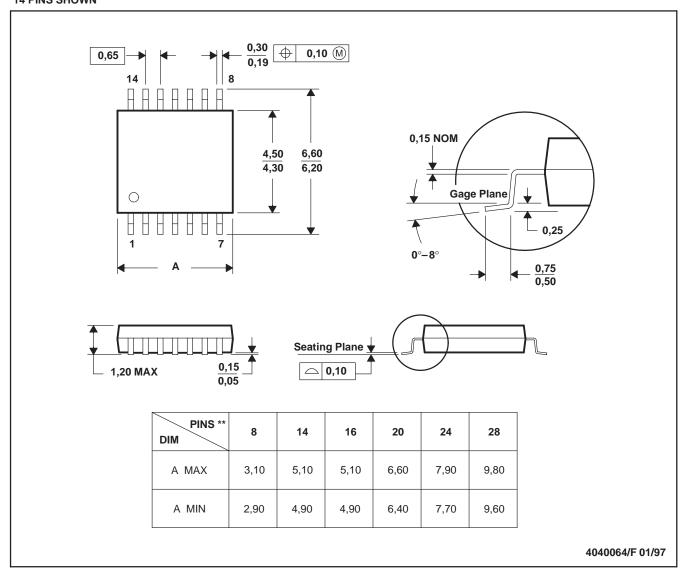
- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



## PW (R-PDSO-G\*\*)

## 14 PINS SHOWN

#### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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